

Search Notes



Application/Control No.

10/014,908

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

CIRCENIS, EDGAR

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	6/06	DBN
	7	↓	↓
	8	↓	↓
	9	↓	↓
	10	↓	↓
711	14A	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	6/06	DBN
Patent PG Pub	↓	↓
II FOREIGN		
EPO, JPO, Derwent	↓	↓
III NPL/dialogs	↓	↓